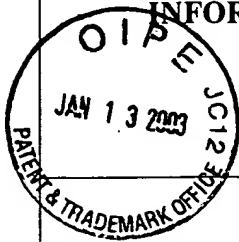


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Docket: 1011-54375

App: 09/620,021

Applicant: Rajski et al.

Filed: July 20, 2000

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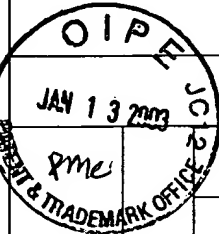
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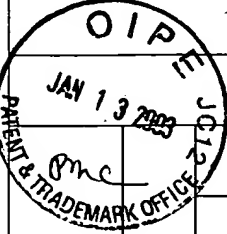
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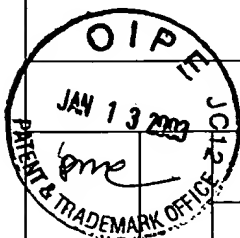
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